

additional categories of awards, to recognize: Volunteer of the Year; Non-governmental Organization of the Year; Excellence in Promoting Cultural & Ethnic Diversity; Excellence in Business Leadership; and the Susan Snow Cotter Award for Excellence in Ocean and Coastal Resource (NOAA re-named this award in honor of Susan Snow Cotter in 2007).

Affected Public: State, local and Tribal governments; not-for-profit institutions.

Frequency: Biannually.

Respondent's Obligation: Voluntary.

OMB Desk Officer: David Rostker, (202) 395-3897.

Copies of the above information collection proposal can be obtained by calling or writing Diana Hynek, Departmental Paperwork Clearance Officer, (202) 482-0266, Department of Commerce, Room 7845, 14th and Constitution Avenue, NW., Washington, DC 20230 (or via the Internet at dHynek@doc.gov).

Written comments and recommendations for the proposed information collection should be sent within 30 days of publication of this notice to David Rostker, OMB Desk Officer, FAX number (202) 395-7285, or David_Rostker@omb.eop.gov.

Dated: September 22, 2009.

Gwellnar Banks,

Management Analyst, Office of the Chief Information Officer.

[FR Doc. E9-23290 Filed 9-25-09; 8:45 am]

BILLING CODE 3510-22-P

DEPARTMENT OF COMMERCE

International Trade Administration

Application(s) for Duty-Free Entry of Scientific Instruments

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States. Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be postmarked on or before October 19, 2009. Address written comments to Statutory Import Programs Staff, Room 3720, U.S. Department of Commerce, Washington, D.C. 20230. Applications may be examined between 8:30 A.M. and 5:00 P.M. at the U.S. Department of Commerce in Room 3720.

Docket Number: 09-051. Applicant: University of Notre Dame, 709 Grace Hall, Notre Dame, IN 46556. Instrument: Electron Microscope. Manufacturer: FEI Company, Czech Republic. Intended Use: The instrument will be used for the fabrication and characterization of nanostructures. This instrument provides the capability of both direct-write fabrication of nanostructures and nanomodified materials by using the 30 keV Ga⁺ beam to remove material selectively or deposit material by ion-beam induced degradation of gas-phase precursors. Justification for Duty-Free Entry: No instruments of same general category are manufactured in the United States. Application accepted by Commissioner of Customs: August 31, 2009.

Docket Number: 09-052. Applicant: Youngstown State University, One University Plaza, Youngstown, OH 44555. Instrument: Electron Microscope. Manufacturer: JEOL Ltd., Japan. Intended Use: The instrument will be used to study the nonstructural features of materials such as ceramic-metallic composite materials, and how they relate to macroscopic properties such as strength and resistance to corrosion. Justification for Duty-Free Entry: No instruments of same general category are manufactured in the United States. Application accepted by Commissioner of Customs: September 4, 2009.

Docket Number: 09-053. Applicant: University of Notre Dame, 709 Grace Hall, Notre Dame, IN 46556. Instrument: Electron Microscope. Manufacturer: FEI Company, the Netherlands. Intended Use: The instrument will be used for the fabrication and characterization of nanostructures. This instrument provides the capability of both direct-write fabrication of nanostructures and nanomodified materials by using the 30 keV Ga⁺ beam to remove material selectively or deposit material by ion-beam induced degradation of gas-phase precursors. Justification for Duty-Free Entry: No instruments of same general category are manufactured in the United States. Application accepted by Commissioner of Customs: September 9, 2009.

Docket Number: 09-054. Applicant: University of Nebraska Medical Center, 986395 Nebraska Medical Center, Omaha, NE 68198. Instrument: Electron Microscope. Manufacturer: FEI Company, Czech Republic. Intended Use: The instrument will be used to study biological (e.g., human biopsy material and various animal tissues) as well as non-biological materials (e.g., nanoparticles). In studying these materials, the instrument will be used in techniques such as fixation, embedding,

sectioning and staining. Justification for Duty-Free Entry: No instruments of same general category are manufactured in the United States. Application accepted by Commissioner of Customs: September 11, 2009.

Dated: September 22, 2009.

Christopher D. Cassel,

Director.

IA Subsidies Enforcement Office.

[FR Doc. E9-23383 Filed 9-25-09; 8:45 am]

BILLING CODE 3510-DS-S

DEPARTMENT OF COMMERCE

International Trade Administration

National Renewable Energy Laboratory, *et al.*

Notice of Decision on Application for Duty-Free Entry of an Electron Microscope

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Room 3705, U.S. Department of Commerce, 14th and Constitution Avenue, NW, Washington, D.C.

Docket Number: 09-047. Applicant: Washington State University, Pullman, WA 99164. Instrument: Electron Microscope. Manufacturer: FEI Company, Czech Republic. Intended Use: See notice at 74 FR 44350, August 28, 2009.

Comments: None received. Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as this instrument is intended to be used, was being manufactured in the United States at the time the instrument was ordered. Reasons: The foreign instrument is an electron microscope and is intended for research or scientific educational uses requiring an electron microscope. We know of no electron microscope or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of this instrument.

Dated: September 22, 2009.

Christopher D. Cassel,

Director.

Subsidies Enforcement Office.

Import Administration.

[FR Doc. E9-23384 Filed 9-25-09; 8:45 am]

BILLING CODE 3510-DS-S